

## Problem 1

Firstly, measure the conductivity  $\sigma_n$  without the applied B field as illustrated in the Figure (1).

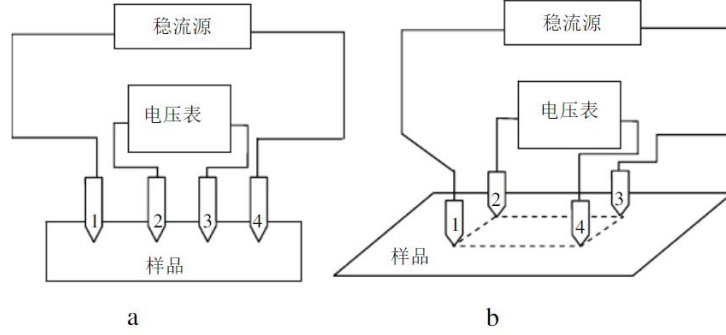


图 1. 四点探针电阻测量原理示意图

Figure 1: Schematic diagram for measuring the conductivity.

When applied B field, the motion of the electrons is shown in Figure (2), which generates the Hall electric field  $E_y$ .

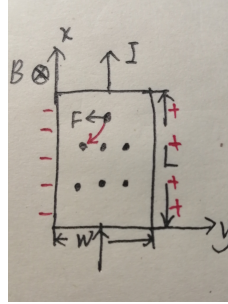


Figure 2: This is the motion of electrons in n type semiconductor with B field.

$$-qE_y - qv_x B = 0 \quad (1)$$

The Hall voltage is known, so the Hall electric field is

$$E_y = \frac{V_H}{W} = -v_x B \quad (2)$$

where the mean drift velocity is  $v_x = -\mu_n E_x$ .

As for  $E_x$ ,

$$E_x = \frac{J}{\sigma_n} = \frac{I}{\sigma_n W D} \quad (3)$$

In conclusion, based on Equation (2) and (3), the mobility of the semiconductor is derived by

$$\mu_n = -\frac{v_x}{E_x} = \frac{V_H}{W B E_x} = \frac{V_H}{W B} \cdot \left( \frac{\sigma_n W D}{I} \right) = \frac{V_H \sigma_n D}{B I} \quad (4)$$

## Problem 2

To determine the carrier concentration in thermal equilibrium, we need to know the density of states (the distribution of the energy states in the energy bands) and the Fermi function (the probability of an energy state being occupied by an electron).

$$g_c(E) = 4\pi V \frac{(2m_n^*)^{3/2}}{h^3} (E - E_c)^{1/2} \quad (5)$$

$$g_v(E) = 4\pi V \frac{(2m_p^*)^{3/2}}{h^3} (E_v - E)^{1/2} \quad (6)$$

$$f(E) = \frac{1}{1 + \exp\left(\frac{E - E_F}{k_0 T}\right)} \quad (7)$$

Assuming a continuous distribution of energy levels in the energy band, we can divide the energy band into infinitely small  $dE$ . Among the energy  $E$  with  $E + dE$ , the distribution of electrons in the conduction band can be found by the product  $g_c(E) f(E) dE$ . And the distribution of holes in the valence band can be found by the product  $g_v(E) [1 - f(E)] dE$ .

The carrier concentration is derived by integrating over all energies:

- Electron concentration

$$n = \int_{E_c}^{\infty} g_c(E) f(E) dE \quad (8)$$

- Hole concentration

$$p = \int_{-\infty}^{E_v} g_v(E) [1 - f(E)] dE \quad (9)$$

In thermal equilibrium, the electron concentration per unit volume is given by

$$\begin{aligned} n_0 = \frac{n}{V} &= \int_{E_c}^{\infty} \exp\left(-\frac{E - E_F}{k_0 T}\right) 4\pi \frac{(2m_n^*)^{3/2}}{h^3} (E - E_c)^{1/2} dE \\ &= 4\pi \frac{(2m_n^*)^{3/2}}{h^3} (k_0 T)^{3/2} \exp\left(-\frac{E_c - E_F}{k_0 T}\right) \int_0^{\infty} x^{1/2} e^{-x} dx \\ &= N_c \exp\left(-\frac{E_c - E_F}{k_0 T}\right) \end{aligned} \quad (10)$$

where  $x = (E - E_c) / (k_0 T)$ ,  $\int_0^{\infty} x^{1/2} e^{-x} dx = \frac{\sqrt{\pi}}{2}$ . The effective density of states for electrons in the conduction band is  $N_c = 2 \frac{(2\pi m_n^* k_0 T)^{3/2}}{h^3}$ .

Similarly, the hole concentration per unit volume is

$$p_0 = N_v \exp\left(\frac{E_v - E_F}{k_0 T}\right) \quad (11)$$

where the effective density of states for holes in the valence band is  $N_v = 2 \frac{(2\pi m_p^* k_0 T)^{3/2}}{h^3}$ .

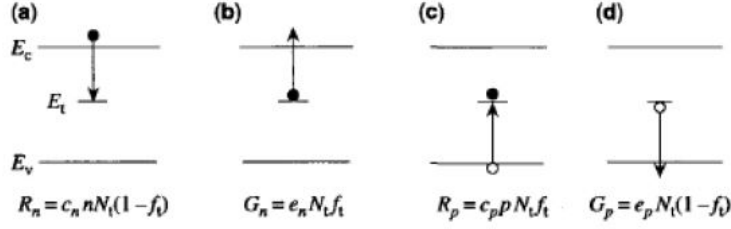
The product of carrier concentration is obtained from

$$n_0 p_0 = N_c N_v \exp\left(-\frac{E_c - E_v}{k_0 T}\right) = N_c N_v \exp\left(-\frac{E_g}{k_0 T}\right) = n_i^2 \quad (12)$$

where  $n_i$  is the intrinsic carrier density.

### Problem 3

The processes of nonradiative Shockley-Read-Hall (SRH) recombination are illustrated in the Figure (1).



(a) electron capture; (b) electron emission; (c) hole capture; (d) hole emission

Figure 1: The four processes of SRH recombination

- Electron capture: The recombination rate for electrons is

$$R_n = c_n n N_t (1 - f_t) \quad (1)$$

- Electron emission: The generation rate of the electrons is

$$G_n = e_n N_t f_t \quad (2)$$

- Hole capture: The recombination rate of the holes is

$$R_p = c_p p N_t f_t \quad (3)$$

- Hole emission: The generation rate of the holes is

$$G_p = e_p N_t (1 - f_t) \quad (4)$$

where  $N_t$  is the concentration of the traps,  $N_t (1 - f_t)$  term represents the concentration of empty traps,  $e_n$  and  $e_p$  are the emission probability for electrons and holes respectively. And  $c_n$  and  $c_p$  are the capture coefficient for the electrons and holes, respectively.

At thermal equilibrium, we have derived the expressions:

$$\frac{e_n}{c_n} = n_1, \frac{e_p}{c_p} = p_1, n_1 p_1 = n_i^2 \quad (5)$$

where  $n_1$  and  $p_1$  are the conduction equilibrium electron carrier concentration and the valence equilibrium hole carrier concentration when the Fermi level is coincident with the recombination center level, respectively.

However,  $f_t$  is unknown in non-equilibrium and has to be calculated. Considering the stable condition  $R_n - G_n = R_p - G_p$ , we have

$$c_n n N_t (1 - f_t) - e_n N_t f_t = c_p p N_t f_t - e_p N_t (1 - f_t) \quad (6)$$

$$f_t = \frac{c_n n N_t + e_p N_t}{e_n N_t + c_p p N_t + c_n n N_t + e_p N_t} = \frac{c_n n + c_p p_1}{c_n (n + n_1) + c_p (p + p_1)} \quad (7)$$

So the SRH recombination rate is derived by

$$U = R_n - G_n = \frac{c_n c_p N_t (np - n_1 p_1)}{c_n (n + n_1) + c_p (p + p_1)} = \frac{np - n_i^2}{\tau_p (n + n_1) + \tau_n (p + p_1)} \quad (8)$$

where  $\tau_p = \frac{1}{c_p N_t}$ ,  $\tau_n = \frac{1}{c_n N_t}$ .

## Problem 4

*Solution.* Carrier concentration in thermal non-equilibrium of holes is

$$p = N_v \exp\left(\frac{E_v - E_{F_p}}{k_B T}\right),$$

where  $N_v$  is the effective density of states for valance band,  $E_v$  is the valence level and  $E_{F_p}$  is the quasi-Fermi level of holes. Then the quasi-Fermi level of holes can be derived as

$$E_{F_p} = E_v - k_B T \ln\left(\frac{p}{N_v}\right) = E_0 - \chi - E_g + k_B T \ln N_v - k_B T \ln p,$$

where  $E_0$  is base level,  $\chi$  is the vacuum level and  $E_g$  is the band gap between the conduction and valence levels. According to quasi-Fermi potential

$$\phi_p = \varphi + \frac{k_B T}{q} \log\left(\frac{p}{n_i}\right)$$

and the defination of electrostatic field

$$\mathbf{E} = -\nabla\varphi,$$

the expression of the hole current can be written as

$$J_p = -q\mu_p p \nabla\phi_p = q\mu_p p \mathbf{E} - qD_p \nabla p,$$

where  $D_p$  satisfies the Einstein relation

$$D_p = \mu_p \frac{k_B T}{q}.$$

Then, the hole current can be also expressed as

$$J_p = -\mu_p p \nabla(q\phi_p) = -\mu_p p \nabla E_{F_p} = -\mu_p p \nabla[E_0 - \chi - E_g + k_B T \ln N_v - k_B T \ln p].$$

In order to derive the expression of electrostatic field of holes (i.e.,  $\mathbf{E}_p$ ), we need to wirte the hole current equation in the form including  $\mathbf{E}$ . Therefore,

$$\begin{aligned} J_p &= q\mu_p p \left[ -\nabla\left(\frac{E_0 - \chi - E_g + k_B T \ln N_v - k_B T \ln p}{q}\right) \right] \\ &= q\mu_p p \left[ -\nabla\left(\frac{E_0 - \chi - E_g + k_B T \ln N_v}{q}\right) \right] - qD_p \nabla p \\ &= q\mu_p p \mathbf{E}_p - qD_p \nabla p \end{aligned}$$

Eventually, we get

$$\begin{aligned} \mathbf{E}_p &= -\nabla\phi_p = -\nabla\left(\frac{E_0 - \chi - E_g + k_B T \ln N_v}{q}\right) \\ \phi_p &= \frac{E_0 - \chi - E_g + k_B T \ln N_v}{q} = \varphi + \frac{\chi}{q} + \frac{E_g}{q} - \frac{k_B T}{q} \ln N_v. \end{aligned}$$

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